

David L. Windt

Publications

Peer-Reviewed Journals

1. D. L. Windt, R. P. Conley, E. M. Gullikson, C. Gollwitzer, M. Krumrey, and C. Laubis, 'Bilayer and trilayer X-ray mirror coatings containing W, Pt, or Ir in combination with C, C/Co, B₄C, or B₄C/Ni: X-ray Reflectance, Film Stress, and Temporal Stability', *Appl. Opt.* 62(36), 9568-9576 (2023) doi: 10.1364/AO.496511
2. J. P. Mason, P. C. Chamberlin, D. Seaton, J. Burkepile, R. Colaninno, K. Dissauer, F. G. Eparvier, Y. Fan, S. Gibson, A. R. Jones, C. Kay, M. Kirk, R. Kohnert, W. D. Pesnell, B. J. Thompson, A. M. Veronig, M. J. West, D. Windt, T. N. Woods, 'SunCET: The Sun Coronal Ejection Tracker Concept', *J. Space Weather and Space Climate*, 11, 20, (2021) doi: 10.1051/swsc/2021004
3. L. A. Rachmeler, A. R. Winebarger, S. L. Savage, L. Golub, K. Kobayashi, G. D. Vigil, D. H. Brooks, J. W. Cirtain, B. De Pontieu, D. E. McKenzie, R. J. Morton, H. Peter, P. Testa, S. K. Tiwari, R. W. Walsh, H. P. Warren, C. Alexander, D. Ansell, B. L. Beabout, D. L. Beabout, C. W. Bethge, P. R. Champey, P. N. Cheimets, M. A. Cooper, H. K. Creel, R. Gates, C. Gomez, A. Guillory, H. Haight, W. D. Hogue, T. Holloway, D. W. Hyde, R. Kenyon, J. N. Marshall, J. E. McCracken, K. McCracken, K. O. Mitchell, M. Ordway, T. Owen, J. Ranganathan, B. A. Robertson, M. J. Payne, W. Podgorski, J. Pryor, J. Samra, M. D. Sloan, H. A. Soohoo, D. B. Steele, F. V. Thompson, G. S. Thornton, B. Watkinson & D. Windt, 'The High-Resolution Coronal Imager, Flight 2.1', *Solar Physics*, 294, 174 (2019) doi: 10.1007/s11207-019-1551-2
4. D. L. Windt, 'Monochromatic mammography using scanning X-ray mirrors', *Rev. Sci. Instrum.*, 89, 083702 (2018) doi:10.1063/1.5041799
5. H. L. Marshall, H. Moritz Günther, R. K. Heilmann, N. S. Schulz, M. Egan, T. Hellickson, D. L. Windt, E. M. Gullikson, B. Ramsey, G. Tagliaferri, and G. Pareschi, 'Design of a broad-band soft X-ray polarimeter', *J. Astron. Telesc. Instrum. Syst.*, 4, 011005-1 – 011005-12 (2018), doi: 10.1117/1.JATIS.4.1.011005
6. J. Goldstein, C. R. Chappell, M.W. Davis, M. H. Denton, R. E. Denton, D. L. Gallagher, G. R. Gladstone, M. B. Lecoche, B. R. Sandel, and D. L. Windt, 'Imaging the global distribution of plasmaspheric oxygen', *J. Geo. Res. – Space Physics*, , 123, 2078 – 2103 (2018), doi: 10.1002/2017JA024531
7. D. L. Windt and E. M. Gullikson, 'Pd/B₄C/Y multilayer coatings for extreme ultraviolet applications near 10 nm wavelength', *App. Op.*, 54, 5850 – 5860 (2015); doi: 10.1364/AO.54.005850
8. D. L. Windt, 'Laboratory-based X-ray reflectometer for multilayer characterization in the 15-150 keV energy band', *Rev. Sci. Instrum.*, 86, 043107 (2015); doi: 10.1063/1.4916737
9. K. Kobayashi, J. Cirtain, A. R. Winebarger, K. Korreck, L. Golub, R. W. Walsh, B. De Pontieu, C. DeForest, A. Title, S. Kuzin, S. Savage, D. Beabout, B. Beabout, W. Podgorski, D. Caldwell, K. McCracken, M. Ordway, H. Begner, R. Gates, S. McKillop, P. Cheimets, S. Platt, N. Mitchell, D. Windt, 'Hi-C: The High Resolution Coronal Imager', *Solar Physics* (2014) doi: 10.1007/s11207-014-0544-4
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14. M. G. Pelizzo, A. J. Corso, P. Zuppella, P. Nicolosi, S. Fineschi, J. Seely, B. Kjornrattanawanich, D. L. Windt, 'Long-term stability of Mg/SiC multilayers', *Opt. Eng.* 51, 023801 (2012)
15. M. G. Pelizzo, A. J. Corso, P. Zuppella, D. L. Windt, G. Mattei and P. Nicolosi, 'Stability of EUV multilayer coatings to low energy proton bombardment', *Opt. Ex.* 19, 14838 – 14844 (2011)
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Book Chapters

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